

A STUDY OF MECHANISM OF AN APERTURE- COUPLED DUAL STACKED MICROSTRIP PATCH ANTENNA FED BY COPLANAR WAVEGUIDE

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ABSTRACT

An aperture-coupled stacked patch antennas, fed by coplanar waveguide (CPW) is presented which is to be used at millimetre-wave frequencies. After studying the important design parameters, it was found that impedance matching can easily be achieved by tuning the dimensions of the excitation slot and adding an impedance tuning stub. In this way, an antenna element with a -10 dB impedance bandwidth of over 35 % was designed. This study allows a more efficient design of CPW-fed stacked patch antennas which has led for coupling mechanism between the different resonators.

I. INTRODUCTION

To feed antennas operating at millimeter-wave frequencies (around 30 GHz), Aperture coupling is an interesting technique. Micro strip antennas become very small, reducing the suitability of coaxial feeding, as probes are accompanied by soldering points, introducing parasitic inductances at these frequencies. However, Aperture coupling provides lower parasitic radiation and the centred feed provides higher radiation pattern symmetry [3]. The dimension variation of the aperture facilitates impedance matching [3]. It is known that the coupling of several resonances leads to a significant increase in bandwidth, which is desired in many applications in the field of telecommunications, e.g. for wireless links with high information capacity. In this paper a systematic parameter study of an aperture-coupled stacked dual patch antenna on glass substrates with an intermediate permittivity ($\epsilon_r = 6.2$), fed by CPW is focused and thus eliminating the need for a separate feed substrate, which was required to accommodate the feeding microstrip line in [2]. Recently CPW has several advantages: low dispersion, good characteristic impedance control, easy integration with shunt lumped elements and active devices [1].

CONFIGURATION OF AN ANTENNA

In below Fig. 1, the antenna configuration consists of a ground plane carrying the CPW terminated in an excitation slot, a substrate, a lower square patch, a second substrate on top of it and an upper square patch. The slot is short-circuited by connecting the centre conductor of the CPW to the ground plane. The slot is inductively coupled because the impedance locus lies in the inductive region on the Smith chart. This configuration allows easier impedance matching than its counterpart, the capacitively coupled slot, which is open-circuited [4]. Therefore the inductively coupled excitation slot is chosen for an investigation of the stacked patch

configuration.

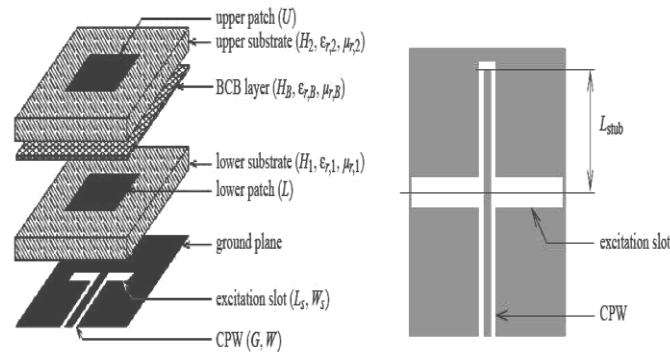


Fig. 1: Stacked patch antenna configuration (left) and impedance tuning stub layout (right)

The lower substrate has thickness H_1 , relative permittivity $\epsilon_{r,1}$ and relative permeability $\mu_{r,1}$. The upper substrate has thickness H_2 , relative permittivity $\epsilon_{r,2}$ and relative permeability $\mu_{r,2}$. A Multi Chip Module technology with deposited thin films (MCM-D) is used to build some test antennas. This technology focuses on glass substrates ($\epsilon_{r,1} = \epsilon_{r,2} = 6.2$ and $\mu_{r,1} = \mu_{r,2} = 1$) for their ease of treatment during the process and for the low material cost. The main interest here was to construct a high bandwidth antenna using these glass substrates, despite the relatively high permittivity. Both substrates are glued together by a thin BenzoCycloButene (BCB) film (with parameters $H_B = 5 \mu\text{m}$, $\epsilon_{r,B} = 2.7$, $\mu_{r,B} = 1$). Because the BCB layer's thickness is very small compared to the considered wavelengths, its influence is negligible. The excitation slot has length L_s and width W_s . The patches are centred with respect to each other and the excitation slot is aligned under the centre of the patches. The coplanar waveguide has a centre conductor width W and a slot width G .

STUDY OF VARIOUS PARAMETERS

Here a systematic parameter study is performed. The dimensions of the CPW are chosen such that an odd mode characteristic impedance of 50Ω is obtained: $G = 25 \mu\text{m}$ and $W = 100 \mu\text{m}$. Resonant frequencies are defined at maxima of the real part of the input

impedance $Z_{in}(f)$. The two patches and the excitation slot in the ground plane form a resonating structure, which exhibits two coupling effects: one between the slot and the lower patch, another between the patches. The self-resonance of the excitation slot lies above the considered frequency band (20–45 GHz). On the Smith chart the impedance locus contains two loops. The larger the radius of such a loop, the greater the coupling factor. Each physical parameter, except for $\epsilon_{r,1}$ and $\epsilon_{r,2}$, will be varied, keeping the other parameters fixed, and its influence will be discussed. Unless mentioned otherwise, the slot width $W_s = 0.1 \text{ mm}$ and the stub length $L_{\text{stub}} = 0.8 \text{ mm}$. The analysis is based on the solution of integral equations solved in the spectral domain by the method of moments. Agilent Technologies' Momentum is used as a simulation tool. For this structure, a mesh of 20 cells per wavelength, combined with edge expansion functions, gives accurate results. The electric and magnetic surface currents are discretized using rooftop expansion functions defined over the cells in the mesh.

By Varying the Excitation Slot Dimensions L_s and W_s

The length L_s of the excitation slot is another parameter which has a considerable influence on the resonant frequencies and on the impedance behaviour. It is observed that f_1 shifts down and R_1 rises as L_s is increased. If $X_1 = \text{Im}fZ_{in}(f)g$, it is observed that $X_1 \propto L_s$, which is a result similar to those in [2], [4] and [6]. Frequency f_2

shifts down for increasing L_s , but this shift is quite small compared to that of f_1 . This seems logical since f_2 is mainly determined by U and the upper patch is somewhat shielded from the excitation slot by the lower patch. On the Smith charts in Fig. 2 the main loop becomes larger for increasing L_s . For a certain value of L_s , this loop will touch the circle $r = 1$. Therefore, this parameter can be used for impedance matching, if the inductive component X_1 can be neutralized. The radius of the small loop increases as L_s is increased, reaches a maximum and decreases again for very large L_s . This smaller loop rotates in a clockwise direction with respect to the main loop as L_s increases.

The parameter W_s has an effect similar to that of L_s . It is observed that f_1 decreases slightly and R_1 as well as X_1 increase almost linearly with increasing W_s .

By Varying the Substrate Thicknesses H_1 and H_2

The first resonance (f_1, R_1) is affected by the thickness H_1 of the lower substrate. The f_1 shifts down as H_1 is increased. The influence of H_1 on the second resonance is small. It is noted that the bandwidth of the first resonance increases as H_1 is increased. On the Smith chart the radius of the lower frequency loop decreases if H_1 is increased. This behaviour was expected as the patch is moved further away from the excitation slot, thus reducing the coupling [5].

The thickness H_2 of the upper substrate has a considerable influence on both resonances and on the input impedance. An important consequence of raising H_2 is an increase in bandwidth. Another observation is that f_2 shifts down more than f_1 if H_2 is increased, so the ratio $f_2 = f_1$ is lowered and the two resonant frequencies lie closer to each other, which is also noted in. The impedance curve versus frequency becomes smoother. On the Smith charts in Fig. 3, the radius of the smaller loop in the impedance locus and the coupling between the two patches decrease as H_2 is raised.

Design Process

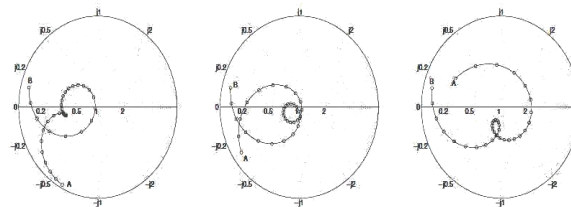


Fig.2 : Impedance loci: (a) $L_s = 1.4$ mm, (b) $L_s = 1.7$ mm and (c) $L_s = 2.0$ mm. Other parameters: $H_1 = 0.3$ mm, $H_2 = 0.7$ mm, $L = 1.4$ mm, $U = 1.4$ mm. Frequency range A-B: 21-38 GHz with 0.5 GHz increments.

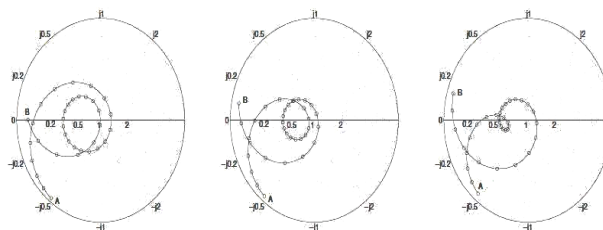


Fig.3 : Impedance loci: (a) $H_2 = 0.5$ mm, (b) $H_2 = 0.6$ mm and (c) $H_2 = 0.7$ mm. Other parameters: $H_1 = 0.3$ mm, $L = 1.4$ mm, $U = 1.45$ mm, $L_s = 1.55$ mm. Frequency range A-B: 21-38 GHz with 0.5 GHz increments.

A tuning stub was added to achieve impedance matching as shown in Fig. 1 for the design of a wide-band test antenna around 30 GHz. The required stub length L_{stub} is shorter for an electrically open-ended stub than for an electrically short-circuited stub and is approximately $\lambda_1/4$, where $\lambda_1 = \lambda_0/\sqrt{\epsilon_1}$ and λ_0 is the free space wavelength [7][8]. This antenna's physical parameters are: $H_1 = 0.3$ mm, $H_2 = 0.7$ mm, $L = 1.4$ mm, $U = 1.425$

mm, $L_s = 1.58$ mm, $W_s = 0.1$ mm. Its main characteristics are: $f_1 = 25.2$ GHz, $f_2 = 33.2$ GHz, $R_1 = R_2 \approx 60 \Omega$. The -10 dB bandwidth is 10.73 GHz or 36.8 %, while the -15 dB bandwidth is still 9.27 GHz or 31.8 % [9]. The antenna gain in broadside direction is about 3 dB and shows two maxima, which are each located higher in frequency than the input resistance maxima at f_1 and f_2 .

II. CONCLUSIONS

For better understanding of the mechanism of an aperture-coupled dual stacked patch configuration fed by coplanar waveguide, more simulations have been done. The summarized results in this paper are of practical importance to designers of this type of antenna element. Careful inspection of the results of this study has allowed to design a wide-band antenna with a -10 dB bandwidth of over 35 %. It is especially for the glass substrates employed in MCM-D technology, but the main trends in the results can surely be extended to substrates with different permittivity's.

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